

In the Claims

1.-7. Canceled

8. (Previously presented) A method for analyzing an object comprising:
prescanning the object using a multiple energy X-ray device to determine prescan information;
transmitting the prescan information to a processor coupled to a computed tomography device;
performing a computed tomography scan of at least a portion of the object based on the prescan information, wherein the computed tomography scan generates computed tomography scan data and is performed using the computed tomography device; and
performing a metal artifact correction on the computed tomography scan data, wherein the prescan information is used to perform the metal artifact correction on the computed tomography scan data.

9. (Original) The method of claim 8, wherein the processor is located within the computed tomography device.

10.-24. Canceled

25. (Previously presented) The method of claim 8, wherein prescanning comprises prescanning the object using a second computed tomography device.

26.-27. Canceled

28. (Previously presented) A method for analyzing an object comprising:
prescanning the object using a multiple energy X-ray device to determine information indicative of effective atomic number characteristics of the object;
transmitting, to another device that is separate from and coupled to the multiple energy X-ray device, a transmission that is based at least partially on the information; and

using the information received at the device to process scan data generated by a computed tomography device.

29. (Previously presented) The method of claim 28, wherein the another device is a processor coupled to the computed tomography device, and wherein at least a portion of the multiple energy X-ray device is not common to the computed tomography device.

30. (Previously presented) The method of claim 28, further comprising:
using the information to select an area of interest of the object based upon the information; and
conducting a scan of the area of interest of the object with the computed tomography device to generate the scan data.

31. (Previously presented) The method of claim 28, wherein using the information received at the device to process scan data comprises using the information to apply a metal artifact correction algorithm to the scan data.

32. (Previously presented) The method of claim 28, wherein the transmission comprises the information.

33. (Previously presented) The method of claim 28, wherein using the information received at the device to process scan data comprises using the information to determine a type of a metal positioned to create a metal artifact in the scan data.

34. (Previously presented) The method of claim 28, wherein using the information received at the device to process scan data comprises using the information to determine a shape of a metal positioned to create a metal artifact in the scan data.

35. (Previously presented) The method of claim 28, wherein using the information received at the device to process scan data comprises using the information to make a decision relating to threat detection.

36. (Previously Presented) The method of claim 28, wherein the multiple energy x-ray device comprises a processor that is separate from the device.